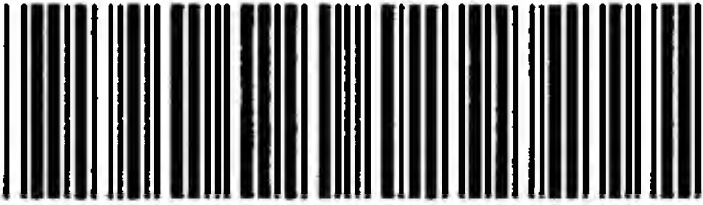


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/054,818	FUKUI ET AL.	
	Examiner	Art Unit	
	Phu K. Nguyen	2628	

SEARCHED			
Class	Subclass	Date	Examiner
345	629-633	2/12/2008	PN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST search - mobile service, effect area, service space, location, acquisition, shape, restrict, constraint, limit, identify	2/12/2008	PN
IEEE, ACM search - mobile service, service, space, area, location, acquisition, shape, restrict, constraint, limit, identify	2/12/2008	PN
Inventor Name search	2/12/2008	PN